

<b>Notice of References Cited</b>	Application/Control No. 10/031,156	Applicant(s)/Patent Under Reexamination JOHNSON ET AL.	
	Examiner Trang U. Tran	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,335,762 B1	01-2002	Lee, Myeong-hwan	348/558
	B	US-5,283,653 A	02-1994	Citta, Richard W.	348/725
	C	US-6,519,298 B1	02-2003	Kim, Ki-bum	375/343
	D	US-6,313,886 B1	11-2001	Sugiyama, Osamu	348/731
	E	US-6,137,546 A	10-2000	Shintani et al.	348/731
	F	US-6,545,723 B1	04-2003	Han, Dong-seog	348/555
	G	US-6,559,898 B1	05-2003	Citta et al.	348/723
	H	US-6,108,044 A	08-2000	Shin, Hyun-soo	348/555
	I	US-6,486,925 B1	11-2002	Ko, Jae-Woo	348/731
	J	US-6,501,510 B1	12-2002	Moon, Yang-choon	348/553
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.